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FDS8870 N-Channel PowerTrench[®] MOSFET

30V, 18A, 4.2m Ω

Features

- r_{DS(on)} = 4.2mΩ, V_{GS} = 10V, I_D = 18A
- r_{DS(on)} = 4.9mΩ, V_{GS} = 4.5V, I_D = 17A
- High performance trench technology for extremely low r_{DS(on)}
- Low gate charge
- High power and current handling capability
- RoHS Compliant

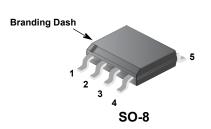


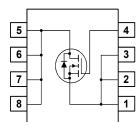
General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{DS(on)}$ and fast switching speed.

Applications

DC/DC converters





April 2007

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Symbol		Parame	ter		Ratings			Units	
V _{DSS}	Drain to Source Voltage			30			V		
V _{GS}	Gate to Source Voltage			±20			V		
		Drain Current							
I_		us (T _A = 25°C, V _{GS} = 10V, R			18			Α	
I _D	Continuou	us (T _A = 25°C, V _{GS} = 4.5V, F	$R_{\theta JA} = 50^{\circ}C/W$			17		A	
	Pulsed				134			Α	
E _{AS}	Single Pulse Avalanche Energy (Note 1)			420			mJ		
P _D	Power dissipation				2.5			W	
	Derate above 25°C				20			mW/ ^c	
T _J , T _{STG}	Operating	and Storage Temperature				-55 to 150)	°C	
Therma	Chara	cteristics							
$R_{ ext{ heta}JC}$	Thermal F	Resistance, Junction to Case	e (Note 2)			25		°C/W	
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient (Note 2a)					50		°C/V	
$R_{ hetaJA}$	Thermal F	Resistance, Junction to Amb	ient (Note 2b)			125		°C/V	
Package	e Marki	ng and Ordering I	nformatio	n					
Device N	larking	Device	Package	Reel Size	Tape	e Width Qu		uantity	
FDS8	-	FDS8870	SO-8	330mm	12r		2500 units		
Symbol	ctorictic	Parameter	Test	Conditions	Min	Тур	Max	Unit	
Off Chara B _{VDSS}	-	source Breakdown Voltage	I _D = 250μA,	$V_{00} = 0V$	30	-	_	V	
20055			V _{DS} = 24V	·GS OF	-	-	1	•	
I _{DSS}	Zero Gate	e Voltage Drain Current	V _{GS} = 0V	T _J = 150 ^o C	-	-	250	μA	
I _{GSS}	Gate to S	ource Leakage Current	V _{GS} = ±20V		-	-	±100	nA	
On Chara	cteristics	5							
V _{GS(TH)}	Gate to S	ource Threshold Voltage	V _{GS} = V _{DS} ,	I _D = 250μA	1.2	-	2.5	V	
00(11)	• •		I _D = 18A, V _{GS} = 10V		-	3.5	4.2		
r	Drain to S	ource On Resistance	I _D = 17A, V ₀		-	3.9	4.9	mΩ	
r _{DS(on)}	Diamito S	ource on Resistance	I _D = 18A, V ₀ T _{.1} = 150 ^o C	I _D = 18A, V _{GS} = 10V,		5.5	7.2	1115.2	
				_	0.0	1.2			
Dynamic	-								
C _{ISS}	Input Cap		V = 15V	$V_{00} = 0 V$	-	4615	-	pF	
C _{OSS}		apacitance	──V _{DS} = 15V, V _{GS} = 0V, f = 1MHz		-	900	-	pF	
C _{RSS}		Fransfer Capacitance			-	450	-	pF	
R _G	Gate Res		V _{GS} = 0.5V,		0.5	2.0	3.5	Ω	
Q _{g(TOT)}		Charge at 10V	$V_{GS} = 0V to$	10V	-	85	112	nC	
Q _{g(5)}		Charge at 5V	$V_{GS} = 0V to$	$5V$ $V_{DD} = 15V$ $I_D = 18A$	-	45	62	nC	
Q _{g(TH)}		Gate Charge	$V_{GS} = 0V$ to	$1V$ $I_g = 1.0mA$	-	4.6	6.0	nC	
Q _{gs}		ource Gate Charge		J.	-	11	-	nC	
	Gate Cha	rge Threshold to Plateau			-	6.4	-	nC	
Q _{gs2} Q _{gd}		rain "Miller" Charge				15		nC	

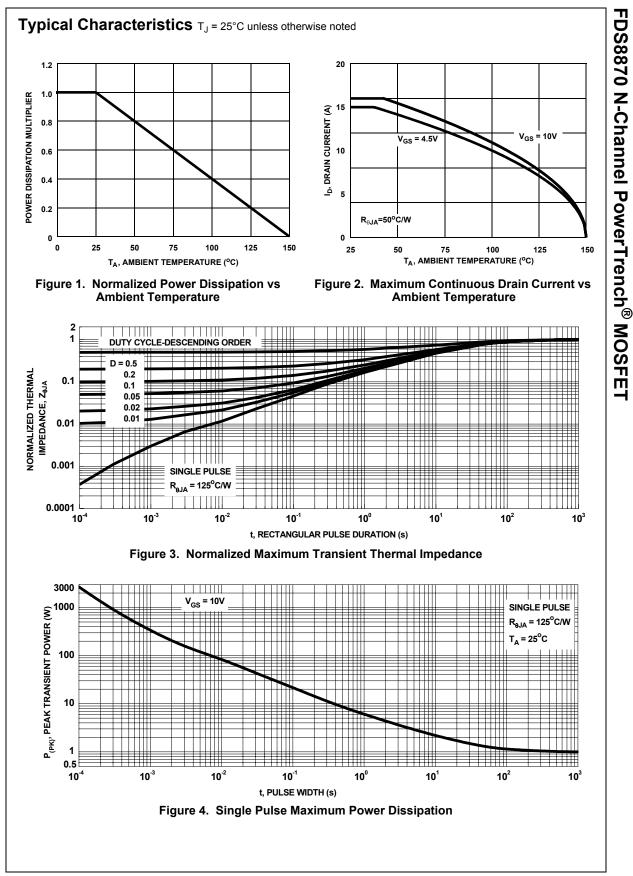
Switchi	Switching Characteristics (V _{GS} = 10V)							
t _{ON}	Turn-On Time		-	-	86	ns		
t _{d(ON)}	Turn-On Delay Time		-	9	-	ns		
t _r	Rise Time	V _{DD} = 15V, I _D = 18A	-	48	-	ns		
t _{d(OFF)}	Turn-Off Delay Time	V_{DD} = 15V, I _D = 18A V _{GS} = 10V, R _{GS} = 3.3Ω	-	60	-	ns		
t _f	Fall Time		-	21	-	ns		
t _{OFF}	Turn-Off Time		-	-	122	ns		

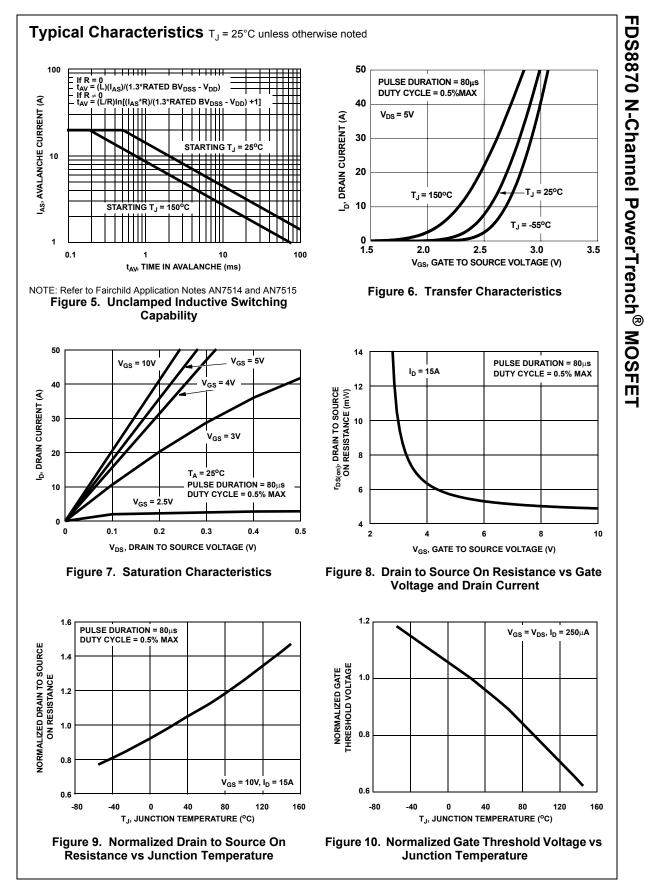
Drain-Source Diode Characteristics

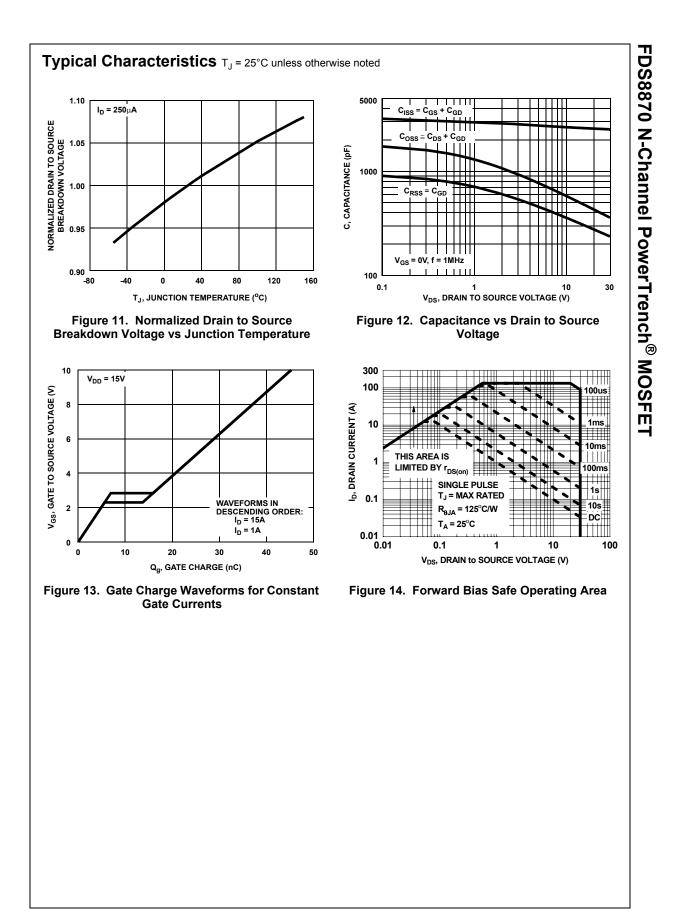
V _{SD}		I _{SD} = 18A	-	-	1.25	V
	Source to Drain Diode Voltage	I _{SD} = 2.1A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	I_{SD} = 18A, d I_{SD} /dt = 100A/µs	-	-	37	ns
Q_{RR}	Reverse Recovered Charge	I_{SD} = 18A, d I_{SD} /dt = 100A/µs	-	-	22	nC

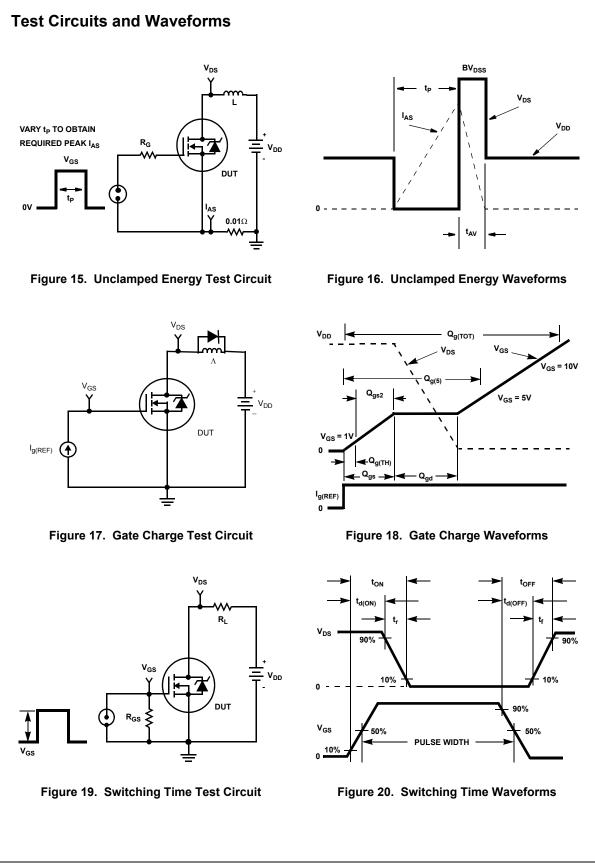
Notes:
1: Starting T_J = 25°C, L = 1mH, I_{AS} = 29A, V_{DD} = 30V, V_{GS} = 10V.
2: R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.
a) 50°C/W when mounted on a 11n² pad of 2 oz copper.

b) 125°C/W when mounted on a minimum pad.









FDS8870 N-Channel PowerTrench[®] MOSFET

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the SO8 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient

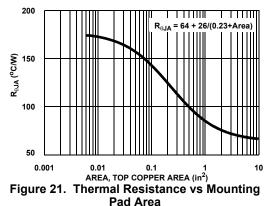
thermal impedance curve.

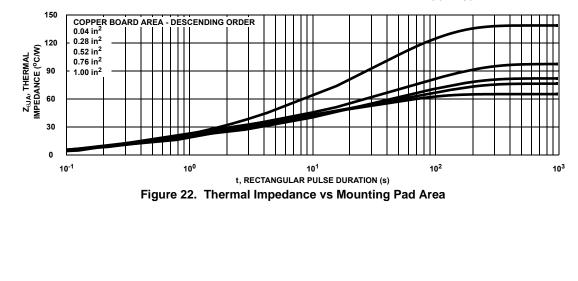
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2. The area, in square inches is the top copper area including the gate and source pads.

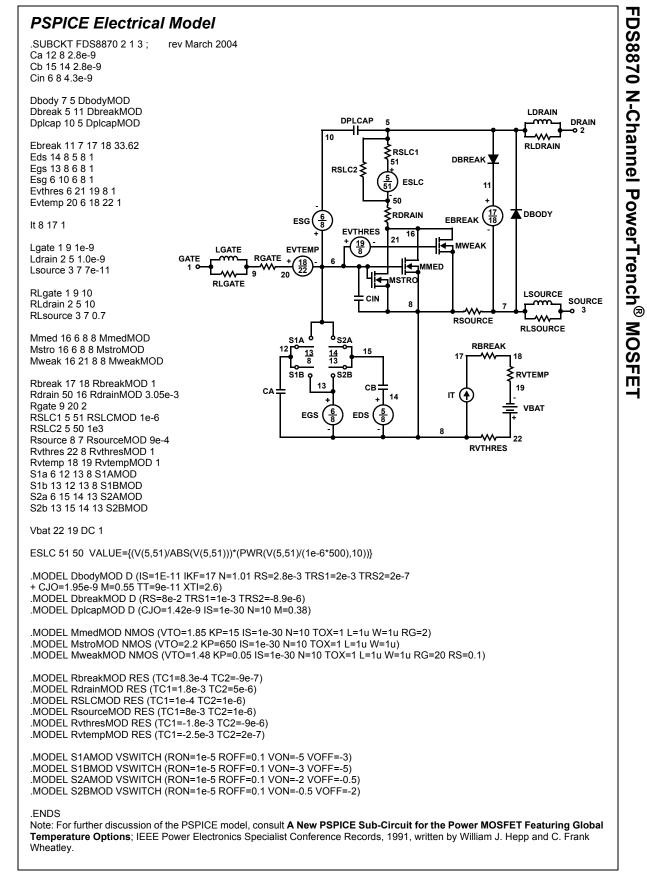
$$R_{\theta JA} = 64 + \frac{26}{0.23 + Area}$$
 (EQ. 2)

The transient thermal impedance (Z_{0JA}) is also effected by varied top copper board area. Figure 22 shows the effect of copper pad area on single pulse transient thermal impedance. Each trace represents a copper pad area in square inches corresponding to the descending list in the graph. Spice and SABER thermal models are provided for each of the listed pad areas.

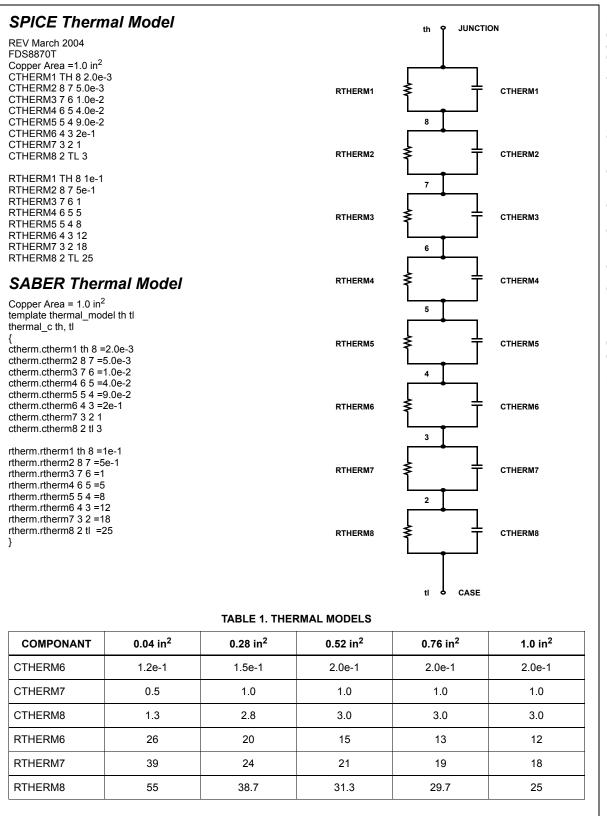
Copper pad area has no perceivable effect on transient thermal impedance for pulse widths less than 100ms. For pulse widths less than 100ms the transient thermal impedance is determined by the die and package. Therefore, CTHERM1 through CTHERM5 and RTHERM1 through RTHERM5 remain constant for each of the thermal models. A listing of the model component values is available in Table 1.







П SABER Electrical Model DS8870 N-Channel PowerTrench[®] MOSFET REV March 2004 template FDS8870 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=1e-11,ikf=17,nl=1.01,rs=2.8e-3,trs1=2e-3,trs2=2e-7,cjo=1.95e-9,m=0.55,tt=9e-11,xti=2.6) dp..model dbreakmod = (rs=8e-2.trs1=1e-3.trs2=-8.9e-6)dp..model dplcapmod = (cjo=1.42e-9,isl=10e-30,nl=10,m=0.38) m..model mmedmod = (type=_n,vto=1.85,kp=15,is=1e-30, tox=1) m..model mstrongmod = (type=_n,vto=2.2,kp=650,is=1e-30, tox=1) m.model mweakmod = $(type=_n, vto=1.48, kp=0.05, is=1e-30, tox=1, rs=0.1)$ sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-5,voff=-3) LDRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3,voff=-5) DPLCAP DRAIN sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-0.5) 10 sw vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.5,voff=-2) RLDRAIN ERSI C1 c.ca n12 n8 = 2.8e-9 c.cb n15 n14 = 2.8e-9 51 RSLC2 > c.cin n6 n8 = 4.3e-9 Ŧ ISCL dp.dbody n7 n5 = model=dbodymod 50 DBREAK dp.dbreak n5 n11 = model=dbreakmod €rdrain <u>6</u> 8 ESG 11 dp.dplcap n10 n5 = model=dplcapmod DBODY EVTHRES 16 21 spe.ebreak n11 n7 n17 n18 = 33.62 <u>19</u> 8 MWEAK LGATE EVTEMP spe.eds n14 n8 n5 n8 = 1 GATE RGATE ■_____MMED EBREAK 18 22 spe.egs n13 n8 n6 n8 = 1 \sim 9 20 spe.esg n6 n10 n6 n8 = 1 RLGATE spe.evthres n6 n21 n19 n8 = 1 LSOURCE CIN SOURCE spe.evtemp n20 n6 n18 n22 = 1 8 3 • RSOURCE i.it n8 n17 = 1 RLSOURCE I.lgate n1 n9 = 1e-9 RBRFAK <u>14</u> 13 15 13 I.Idrain n2 n5 = 1.0e-9 17 18 l.lsource n3 n7 = 7e-11 RVTEMP S2B 13 CB 19 res.rlgate n1 n9 = 10 CA IT 14 (🔺 res.rldrain n2 n5 = 10 VBAT res.rlsource n3 n7 = 0.7 EGS EDS 5 m.mmed n16 n6 n8 n8 = model=mmedmod, I=1u, w=1u 22 m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u RVTHRES m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=8.3e-4,tc2=-9e-7 res.rdrain n50 n16 = 3.05e-3, tc1=1.8e-3,tc2=5e-6 res.rgate n9 n20 = 2 res.rslc1 n5 n51 = 1e-6, tc1=1e-4,tc2=1e-6 res.rslc2 n5 n50 = 1e3 res.rsource n8 n7 = 9e-4, tc1=8e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-1.8e-3,tc2=-9e-6 res.rvtemp n18 n19 = 1, tc1=-2.5e-3,tc2=2e-7 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/500))** 10)) }



DS8870 N-Channel PowerTrench[®] MOSFET

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